## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applic	ants: Jason D. Bivens et al.	)
	•	) Art Unit: unknown
Serial 1	No.: unknown	)
Filed:	concurrently herewith	) Examiner: Unknown
For:	SYSTEM AND METHOD FOR	)
	MEASURING MATERIAL ADDED TO A	)
	VESSEL UNDER A VACUUM	)

## **INFORMATION DISCLOSURE STATEMENT**

ASSISTANT COMMISSIONER FOR PATENTS Washington, D.C. 20231

SIR:

The following documents are known to Applicants or Applicants' attorneys and are submitted for the Examiner to consider in the above-captioned application.

## **U. S. PATENTS**

- U.S. Patent No. 5,004,400 issued April 2, 1991 to Wayne A. Handke.
- U.S. Patent No. 5,027,267 issued June 25, 1991 to Alan J. Pitts et al.
- U.S. Patent No. 5,102,281 issued April 7, 1992 to Wayne A. Handke.
- U.S. Patent No. 5,174,320 issued December 29, 1992 to Thomas E. Allen.
- U.S. Patent No. 5,538,286 issued July 23, 1996 to Thomas M. Hoff.

## Form PTO-1449 is submitted herewith.

Respectfully submitted,

JOHN W. WUSTENBERG Registration No. 35,415

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580-251-3782

FORM PTO-1449 (Modified)				ATTY. DOCKET NO. 2003-IP-011909U1		SERIAL NO. unknown				
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT				APPLICANT Jason D. Bivens et al.						
(Use several sheets if necessary)			FILING DATE concurrently herewith		GROUP unknown					
			L	I.S. PATENT DOCUMENTS		-				
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EXAMINER							1	e if		
INITIAL		Document No.	Date	Name	Class	Subclass	Appro	priate		
	ĀΑ	5,004,400	04/02/91	Handke	414	786				
	AB	5,027,267	06/25/91	Pitts et al.	364	172				
	ÀC	5,102,281	04/07/92	Hankde	414	296				
	AD	5,174,320	12/29/92	Allen	137	1				
	AE	5,538,286	07/23/96	Hoff	280	837				
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.